

Surface Analysis Laboratory XPS and TOF-SIMS

Never Stand Still

Mark Wainwright Analytical Centre

Solid State and Elemental Analysis Unit

Request for TOF-SIMS surface analysis (UNSW)

Date		Sch	School / Department			
Analysis requested by		Sup	Supervisor's Name			
Contact Phone		Sup	Supervisor's Phone			
Contact Email		Sup	Supervisor's Email			
Account for Charges: * 1. Project Code	* 1.	*	★ Supervisor/Manager's Signature		*	
* 2. Fund Code	* 2.	(au	(authorizing charges) or date of email (email authorizing charges)			
* 3. Dept ID	* 3.	(em				
Sample names and	Description (de	tailed info should be a	attached se	parately) :		
1			7			
2			8			
3			9			
4			10			
5			11			
6			12			
Do you want the sa What Analyses are	-	☐ Yes		□No		
☐ TOF-SIN	vio mass specira					
☐ TOF-SIN	MS depth profile f	or elements or peaks o	f			
F	Preferred sputter	source	\square O ₂ or	☐ Cs	or \square Ar _n .	
☐ TOF-SIMS imaging for elements or peaks of						
☐ TOF-SIN	☐ TOF-SIMS 3D imaging for elements or peaks of					
☐ Anything else (please specify in a separate paper if needed)						
What further sample preparation is required?						
Further comments: (eg. Special instructions, priority, importance, required by date, etc)						
r articl comments. (cg. opecial motifications, priority, importance, required by date, cto)						
0.4 MDL 50 W/W L NOT DE KEDT DI 5.4.05 001 L 50T TUEM W/TUIN 4 W/55K0 - (100U5 - (10						
SAMPLES WILL <u>NOT</u> BE KEPT. PLEASE COLLECT THEM WITHIN 4 WEEKS of ISSUE of RESULTS.						
* NB. The analysis jobs will not commence unless the account details are provided						
Office Use Only						
3c 30c 3y		Time taken on analysis		Charge	 e	
Rate \$70	/hour	,				